

Title (en)

Time-of-flight mass spectrometer ion source for gas sample analysis

Title (de)

Flugzeitmassenspektrometerionenquelle zur Analyse von Gasproben

Title (fr)

Source ionique pour spectromètre de masse à temps de vol analysant des échantillons gazeux

Publication

**EP 1052672 B1 20041013 (FR)**

Application

**EP 00401028 A 20000413**

Priority

FR 9905088 A 19990422

Abstract (en)

[origin: US2003057378A1] In accordance with the invention, the ion source of a time-of-flight mass spectrometer includes an electron gun having an electron source and at least one electrode for conditioning the flow of electrons, followed by at least one microchannel wafer for generating a pulsed secondary electron beam containing a greater number of electrons from a pulsed primary electron beam. The secondary electron beam enters a gas ionization area of an ion gun which produces a flow of ions which is then passed through the flight tube in order to be analyzed by an ion detector. This provides a high-performance ion source which is compact, sensitive and easy to integrate.

IPC 1-7

**H01J 27/04**; **H01J 49/10**

IPC 8 full level

**G01N 27/62** (2006.01); **H01J 27/04** (2006.01); **H01J 37/063** (2006.01); **H01J 37/073** (2006.01); **H01J 49/10** (2006.01); **H01J 49/14** (2006.01); **H01J 49/40** (2006.01)

CPC (source: EP US)

**H01J 27/04** (2013.01 - EP US); **H01J 49/08** (2013.01 - EP); **H01J 49/10** (2013.01 - US); **H01J 49/147** (2013.01 - EP); **H01J 43/246** (2013.01 - EP)

Designated contracting state (EPC)

AT BE CH CY DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

DOCDB simple family (publication)

**US 2003057378 A1 20030327**; **US 6545269 B1 20030408**; AT E279783 T1 20041015; DE 60014758 D1 20041118; DE 60014758 T2 20060309; EP 1052672 A1 20001115; EP 1052672 B1 20041013; FR 2792773 A1 20001027; FR 2792773 B1 20010727; JP 2000348665 A 20001215; JP 4395584 B2 20100113

DOCDB simple family (application)

**US 55017100 A 20000414**; AT 00401028 T 20000413; DE 60014758 T 20000413; EP 00401028 A 20000413; FR 9905088 A 19990422; JP 2000116162 A 20000418